



Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number.

Substitute for form 1449/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Complete if Known	
				Application Number	10/081,733
				Filing Date	February 22, 2002
				First Named Inventor	Richard L. Lachance
				Art Unit	N/A
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	6670/1K338US1

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
SP	AA	US-6,101,301-B1	08-08-2000	Engelberth et al.	
SP	AB	US-5,774,619-B1	06-30-1998	Bruesselbach	
SP	AC	US-6,144,789-B1	11-07-2000	Engelberth et al.	
SP	AD	US-5,844,667-B1	12-01-1998	Maron	

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ² -Number ³ -Kind Code ⁴ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
SP	BA	WO-WO 95/30926-A1	11-16-1995	Peter Hill, et al.	
SP	BB	JP-200012184	04-28-2000	Toshiki Sakamoto	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.33). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the application number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

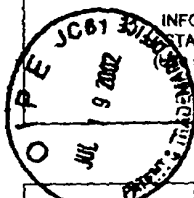
NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
SP	CA	Patent Abstracts of Japan, vol. 2000 no. 7, September 29, 2000 JP 2000 121844 (Furukawa Electric Co. Ltd.) April 28, 2000 Abstract, figure 3.	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature	<i>Sung Park</i>	Date Considered	12/31/03
--------------------	------------------	-----------------	----------

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE (Rev. 2-32)	INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Indicate on this form whether or not the information is contained in several sheets if necessary)		ATTY. DOCKET NO. 6670/1K338US1	SERIAL NO. 10/081,733
	APPLICANT Richard L. LACHANCE et al.		FILING DATE February 22, 2002	GROUP 2874



U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SP	1	4 9 3 6 6 4 6	1990	ENOCHS et al.	350	96.20	
SP	2	5 0 0 7 7 0 5	1991	MOREY et al.	350	96.29	
SP	3	5 0 4 2 8 9 8	1991	MOREY et al.	385	37	
SP	4	5 6 9 4 5 0 3	1997	FLEMING et al.	385	37	
SP	5	5 9 9 1 4 8 3	1999	ENGELBERTH	385	37	
SP	6	6 0 4 4 1 8 9	2000	MILLER	385	37	
SP	7	6 0 8 7 2 8 0	2000	BEALL et al.	501	7	
SP	8	6 1 0 1 3 0 1	2000	ENGELBERTH et al.	385	37	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
SP	9	WO 9 8 5 9 2 6 7	1998	PCT	G02B			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

SP	10	G.W. Yoffe, P.A. Krug, F. Ouellette, and D. Thorncraft, "Temperature-compensated optical-fiber Bragg gratings", OFC, Vol. 8, 1995 OSA Technical Digest Series, Paper W14, p.134;
SP	11	G.W. Yoffe, P.A. Krug, F. Ouellette and D.A. Thorncraft, "Passive temperature-compensating package for optical fiber gratings", Appl. Optics, Vol. 34, No. 30, Oct. 1995, pp. 6858-6861;
SP	12	T.E. Hammon, J. Bulman, F. Ouellette & S.B. Poole, "A temperature compensated optical fiber Bragg grating band rejection filter and wavelength reference", OECC'98 Technical Digest, pp.350-351, 1998.
SP	13	D.L. Weidman, G.H. Beall, K.C. Chyung, G.L. Francis, R.A. Modavis, and R.M. Morena, "A novel negative expansion substrate material for athermalizing fiber Bragg gratings", 22 nd European Conference on Optical Communication - ECOC'96, Oslo, Paper MoB 3.5 pp.1-61.63
SP	14	A. Inoue, T. Iwashima, T. Enomoto, S. Ishikawa and H. Kanamori, "Optimization of fiber Bragg grating for dense WDM transmission system", IEICE Trans. Electron. Vol. E81-C, No. 8, pp 1209-1218, August 1998
SP	15	D. Weidman, "Fiber Bragg gratings enhance real-world applications", Laser Focus World, pp.99-103; March 1999.
SP	16	T. Iwashima, A. Inoue, M. Shigematsu, M. Nishimura, Y. Hattoni, "Temperature compensation technique for fiber Bragg gratings using liquids crystalline polymer tubes", Electronics Letters, Vol. 33, No. 5, pp.417-419, Feb. 27, 1997.
SP	17	S. Magne, S. Rougeault, M. Vilela, and P. Ferdinand, "State-of-strain evaluation with fiber Bragg grating rosettes: application to discrimination between strain and temperature effects in fiber sensors", App. Optics, Dec. 1997, Vol. 36, No. 36, pp. 9437-9442.
SP	18	V. Arya, D.W. Sherrer, A. Wang, R.O. Claus, and Mark Jones, "Application of Thin-Film Optical Filters to the Temperature Compensation of Optical Fiber Grating-Based Devices" IEEE Trans on Instrum. and Meas. Vol.45, No. 5, Oct.1997, pp. 1173-1177.

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sung Park

12/31/03